

## ABSTRACT OF THE DISCLOSURE

5 A test mode signal generating circuit is provided with a test setting control unit for detecting that an external power supply potential exceeds a predetermined potential. When external power supply potential is a high potential beyond a predetermined standard range, a test mode can be set without setting a signal for test mode entry to be a high potential. Therefore, a semiconductor device which can be set in a test mode by an address key in the case of conducting a test by applying a high power supply voltage can be provided.